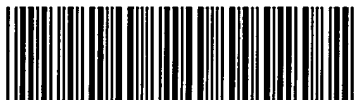


Search Notes

Application/Control No.

10/676,445

Examiner

Sun J. Lin

Applicant(s)/Patent under
Reexamination

SINGH ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	10	1/18/2006	JSL
716	6	1/18/2006	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	10	1/18/2006	JSL
716	6	1/18/2006	JSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO;DERWENT; IBM_TDB]	1/18/2006	JSL
IEEE	1/18/2006	JSL